

MAR. 07 2005

Sheet 1 of 1

Form PTO 1449 Rev. 7-80	U.S. Department of Commerce Patent and Trademark Office LIST OF PRIOR ART CITED BY APPLICANT (Use Several Sheets If Necessary)	Atty. Docket No PO-7865/MD-02-02-B	Serial No. 10/626,368
		Applicant William E. Slack et al	
		Filing Date July 24, 2003	Group 1714

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/KP/	AA	3,367,956	02/06/68	Hennig et al	260	453	
/KP/	AB	5,219,975	06/15/93	Schmalstieg et al	528	45	
/KP/	AC	5,880,174	03/09/99	Singh et al	523	142	
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
/KP/	AL	1 321 930	07/04/73	Great Britain				
/KP/	AM	0 211 630 A2	02/25/87	Europe				
	AN							
	AO							
	AP							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/KP/	AR	Wagner, W.: "Dr." Angew. Chem., vol. 74, no. 21, 1962, pages 799-801, XP009042387
	AS	
	AT	

EXAMINER	/Karl Puttlitz/	DATE CONSIDERED	07/30/2007
EXAMINER Initial if references considered, whether or not citation is in conformance with MPEP 609: Draw line through if not in conformance and not considered. Include copy of this form with next communication to applicant.			

Neither English Language Equivalent nor an English Language Translation is available.

Form PTO 1449 Rev. 7-80	U.S. Department of Commerce Patent and Trademark Office LIST OF PRIOR ART CITED BY APPLICANT (Use Several Sheets If Necessary)	Atty. Docket No. PO-7865 / MD-02-02B	Serial No. To Be Assigned
		Applicant William E. Slack et al	
		Filing Date Herewith	Group

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/KP/	AA	4,456,709	06/26/84	Richter et al	521	160	
/KP/	AB	4,618,706	10/21/86	Scholl et al	560	335	
/KP/	AC	4,677,136	06/30/87	Rasshofer et al	521	159	
/KP/	AD	4,703,100	10/27/87	Rasshofer et al	528	66	
/KP/	AE	4,837,359	06/06/89	Woynar et al	560	335	
/KP/	AF	5,212,275	05/18/93	Slack et al	528	67	
/KP/	AG	5,310,053	05/10/94	Lowry et al	206	310	
/KP/	AH	5,310,054	05/10/94	Stumpff et al	206	310	
/KP/	AI	5,428,124	06/27/95	Slack et al	528	60	
/KP/	AJ	5,440,003	08/08/95	Slack	528	48	
/KP/	AK	5,994,491	11/30/99	Woynar et al	528	68	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
/KP/	AL	197 07 577	08/27/98	Germany				X
	AM							
	AN							
	AO							
	AP							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

EXAMINER	/Karl Puttlitz/	DATE CONSIDERED	07/30/2007
EXAMINER Initial if references considered, whether or not citation is in conformance with MPEP 609: Draw line through if not in conformance and not considered. Include copy of this form with next communication to applicant.			

* Neither English Language Equivalent nor an English Language Translation is available.

Form PTO 1449
Rev. 7-80U.S. Department of Commerce
Patent and Trademark Office
LIST OF PRIOR ART CITED BY APPLICANT
(Use Several Sheets If Necessary)Atty. Docket No.
PO-7865 / MD-02-02BSerial No.
To Be AssignedApplicant
William E. Slack et alFiling Date
Herewith

Group

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/KP/	AA	6,028,158	02/22/00	Slack et al	528	44	
/KP/	AB	6,063,891	05/16/00	Slack et al	528	59	
/KP/	AC	6,271,279 B1	08/07/01	Nodelman et al	521	159	
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

EXAMINER

/Karl Puttlitz/

DATE CONSIDERED

07/30/2007

EXAMINER Initial if references considered, whether or not citation is in conformance with MPEP 609: Draw line through if not in conformance and not considered. Include copy of this form with next communication to applicant.

* Neither English Language Equivalent nor an English Language Translation is available.